## Supplementary Information

# Non-enzymatic Amperometric Sensing of Glucose by Employing Sucrose Templated Microspheres of Copper Oxide (CuO) 

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## Figure Captions:

Fig. S1 Nitrogen adsorption-desorption isotherm of CMS, inset shows the table of obtained parameters.

Fig. S2 Size distribution of CMS obtained by DLS.

Fig. S3 XRD spectra of (a) CSPE and (b) MCSPE.

Fig. S4 Amperometric response of MCSPE towards successive injections of glucose in (a) 30 mM , (b) 50 mM and (c) 100 mM NaOH solution.

Table S1. Circuit parameters obtained from fitting of EIS spectra.


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Table S1. Circuit parameters obtained from fitting of EIS spectra.

| Circuit <br> measurement | Bare electrode <br> without Glucose | Bare Electrode <br> with Glucose | MCSPE without <br> Glucose | MCSPE with <br> glucose |
| :---: | :---: | :---: | :---: | :---: |
| $\mathbf{R}_{\mathbf{s}}(\boldsymbol{\Omega})$ | 172 | 198 | 177.9 | 157.3 |
| $\mathbf{R}_{\mathrm{ct}}(\boldsymbol{\Omega})$ | 2787 | 1835 | 1364 | 1156 |
| $\mathbf{C}_{\mathbf{d l}}(\boldsymbol{\mu \mathbf { F } )}$ | 57.19 | 30.09 | 395 | 470 |

Where:
$\mathrm{R}_{\mathrm{s}}$ corresponds to resistance due to electrolyte and test set up.
$\mathrm{R}_{\mathrm{ct}}$ tells the charge transfer resistance inside the material.
$\mathrm{C}_{\mathrm{dl}}$ is the capacitance due to formation of depletion region in semiconductor.

